

FCC ID: 2APDQM-BLE01

Portable device

According to §15.247(e)(i) and §1.1307(b)(1), systems operating under the provisions of this section shall be operated in a manner that ensures that the public is not exposed to radio frequency energy level in excess of the Commission's guidelines.

According to KDB447498 D01 General RF Exposure Guidance V06

The 1-g SAR and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances \leq 50 mm are determined by:

$[(\text{max. power of channel, including tune-up tolerance, mW}) / (\text{min. test separation distance, mm})] \cdot [\sqrt{f(\text{GHz})}] \leq 3.0 \text{ for 1-g SAR and } \leq 7.5 \text{ for 10-g extremity SAR, where:}$

- $f(\text{GHz})$ is the RF channel transmit frequency in GHz
- Power and distance are rounded to the nearest mW and mm before calculation
- The result is rounded to one decimal place for comparison

When the minimum test separation distance is $<$ 5 mm, a distance of 5 mm is applied to determine SAR test exclusion.

BT:

Modulation	Channel Freq. (GHz)	Conducted power (dBm)	Conducted power (mW)	Tune-up power (dBm)	Max tune-up power (dBm)	Max tune-up power (mW)	Distance (mm)	Result calculation	SAR Exclusion threshold	SAR test exclusion
GFSK	2.402	2.55	1.80	1.6±1	2.6	1.82	<5	0.56405	3.00	YES
	2.441	1.17	1.31	1.6±1	2.6	1.82	<5	0.56861	3.00	YES
	2.480	0.6	1.15	1.6±1	2.6	1.82	<5	0.57313	3.00	YES
$\pi/4$ -DQPSK	2.402	3.33	2.15	2.5±1	3.5	2.24	<5	0.69393	3.00	YES
	2.441	2.17	1.65	2.5±1	3.5	2.24	<5	0.69954	3.00	YES
	2.480	1.52	1.42	2.5±1	3.5	2.24	<5	0.70511	3.00	YES
8DPSK	2.402	3.60	2.29	2.6±1	3.6	2.29	<5	0.71010	3.00	YES
	2.441	2.42	1.75	2.6±1	3.6	2.29	<5	0.71584	3.00	YES
	2.480	1.64	1.46	2.6±1	3.6	2.29	<5	0.72153	3.00	YES
BLE	2.402	4.9	3.09	3.9±1	4.9	3.09	<5	0.95789	3.00	YES
	2.44	4.17	2.61	3.9±1	4.9	3.09	<5	0.96544	3.00	YES
	2.48	2.91	1.95	3.9±1	4.9	3.09	<5	0.97332	3.00	YES

Conclusion:

For the max result : 0.97332W/Kg \leq 3.0 for 1g SAR, No SAR is required.



Signature:

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